TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (High Speed U-MOSII)

# TPC8106-H

High Speed and High Efficiency DC-DC Converters Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

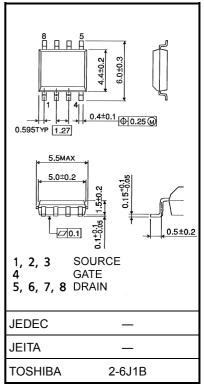
- Small footprint due to small and thin package
- High speed switching
- Small gate charge : Qg = 52 nC (typ.)
- Low drain-source ON resistance  $: R_{DS} (ON) = 14 \text{ m}\Omega (typ.)$
- High forward transfer admittance  $|Y_{fs}| = 16.6 \text{ S (typ.)}$
- Low leakage current  $: I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -30 \ V)$
- Enhancement-mode :  $V_{th} = -0.8 \sim -2.0 \text{ V} (V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA})$

#### Maximum Ratings (Ta = 25°C)

Characte	ristics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	-30	V	
Drain-gate voltage (F	R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	-30	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	۱ <sub>D</sub>	-10	А	
Diameditent	Pulse (Note 1)	I <sub>DP</sub>	-40	~	
Drain power dissipati	on (t = 10 s) (Note 2a)	PD	2.4	W	
Drain power dissipati	on (t = 10 s) (Note 2b)	PD	1.0	W	
Single pulse avalanc	he energy (Note 3)	E <sub>AS</sub>	130	mJ	
Avalanche current		I <sub>AR</sub>	-10	A	
Repetitive avalanche (	energy Note 2a) (Note 4)	E <sub>AR</sub>	0.24	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature	range	T <sub>stg</sub>	−55 to 150	°C	

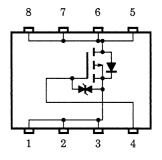
Note: For (Note 1), (Note 2), (Note 3) and (Note 4), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.080 g (typ.)

#### **Circuit Configuration**

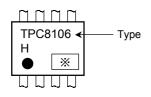


Unit: mm

### **Thermal Characteristics**

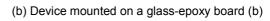
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R <sub>th (ch-a)</sub>	52.1	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	125	°C/W

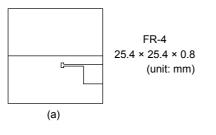
## Marking (Note 5)

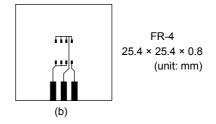


Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)







Note 3: V<sub>DD</sub> = -24 V, T<sub>ch</sub> = 25°C (initial), L = 0.1 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = -10 A

Note 4: Reptitve rating; pulse width limited by maximum channel temperature

Note 5: ● on lower left of the marking indicates Pin 1.

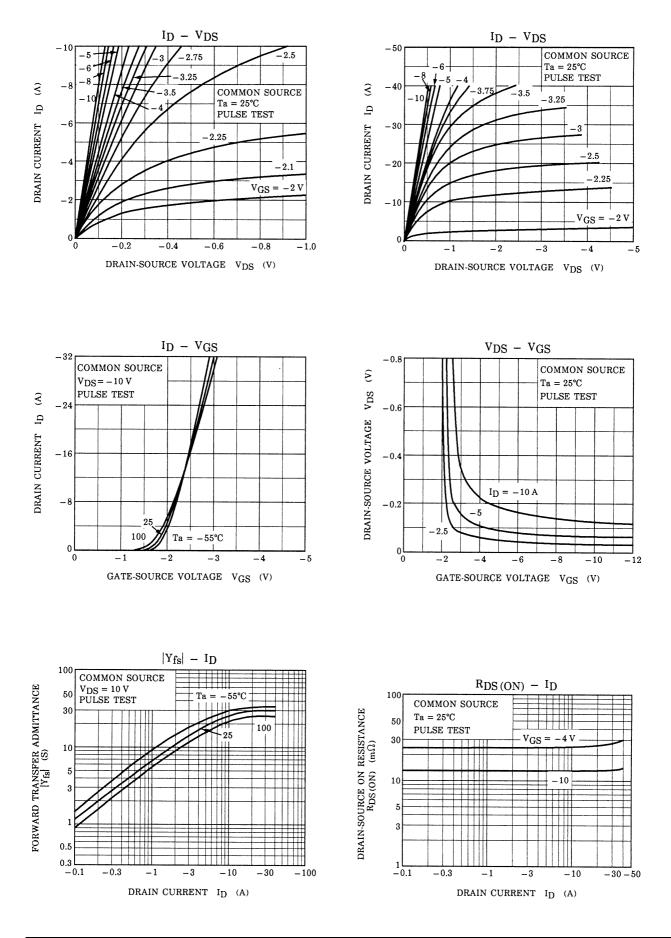
% shows lot number. (year of manufacture: last decimal digit of the year of manufacture, month of manufacture: January to December are denoted by letters A to L respectively.)

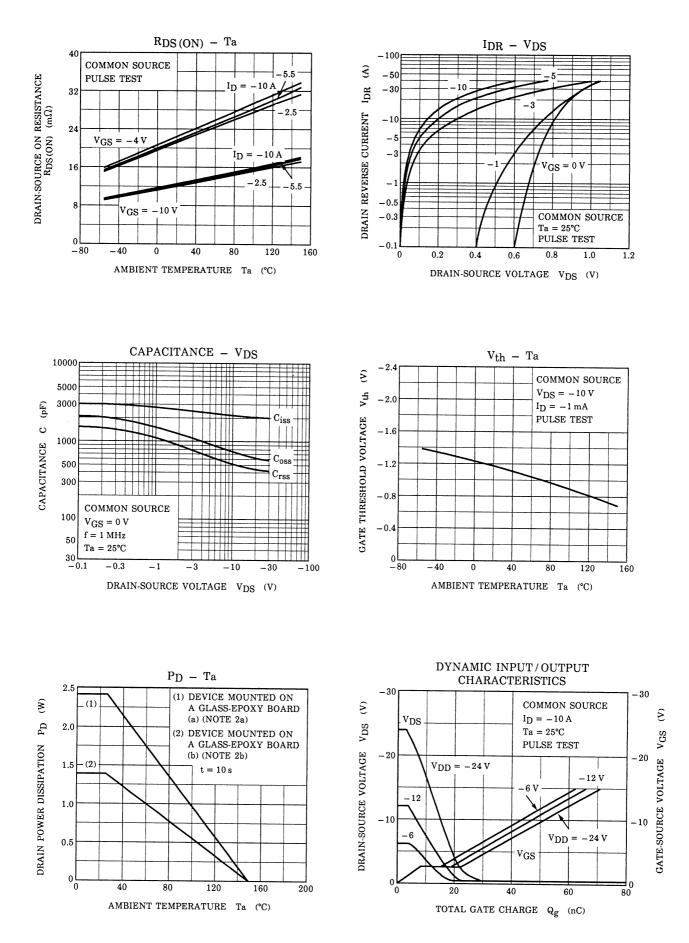
Electrical Characteristics (Ta = 25°C)

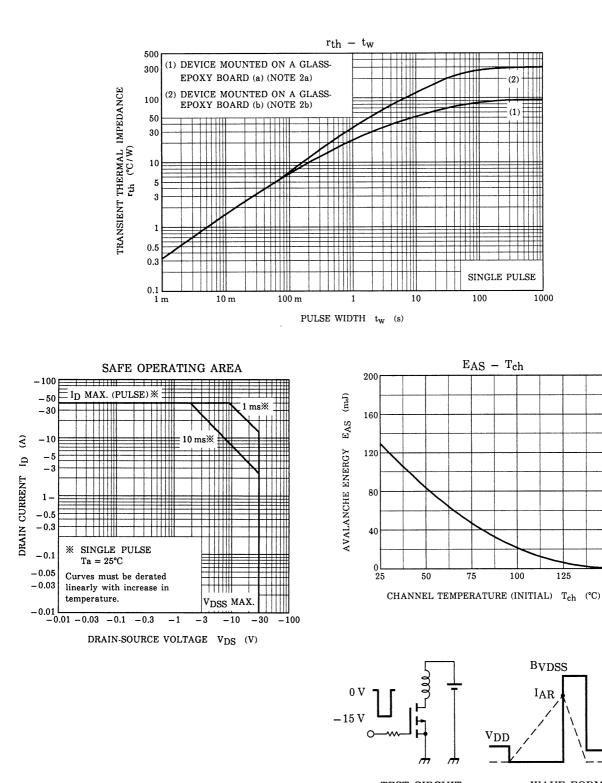
Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-off cu	rrent	I <sub>DSS</sub>	$V_{DS}$ = -30 V, $V_{GS}$ = 0 V			10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_{D}$ = -10 mA, $V_{GS}$ = 0 V	-30	—	—	v
		V (BR) DSX	$I_{\rm D}$ = -10 mA, $V_{\rm GS}$ = 20 V	-15	_	—	
Gate threshold v	voltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = -4 V, I <sub>D</sub> = -5 A	_	24	30	m0
		R <sub>DS (ON)</sub>	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -5 A	_	14	20	mΩ
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -5 A		16.6	_	S
Input capacitance	ce	C <sub>iss</sub>			2160	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS}$ = -10 V, $V_{GS}$ = 0 V, f = 1 MHz	_	530	_	pF
Output capacitance		C <sub>oss</sub>		_	720	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{0}{}_{-10} V \stackrel{I_{D}}{}_{0} \stackrel{I_{D}}{}_{0} \stackrel{O}{}_{0} V_{OUT}$ $\stackrel{0}{}_{10} \stackrel{V}{}_{0} \stackrel{V}{}_{1$	_	12	_	
	Turn-on time	t <sub>on</sub>		_	20	_	
	Fall time	t <sub>f</sub>		_	100	_	ns
	Turn-off time	t <sub>off</sub>		_	250	_	
Total gate charge (Gate-source plus gate-drain)		Qg			52	_	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ −24 V, V <sub>GS</sub> = −10 V, I <sub>D</sub> = −10 A	_	38	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	14	_	

## Source–Drain Ratings and Characteristics (Ta = 25°C)

Charact	eristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	—	Ι	_	-40	А
Forward voltage	(diode)	V <sub>DSF</sub>	I <sub>DR</sub> = -10 A, V <sub>GS</sub> = 0 V	_	_	1.2	V







TEST CIRCUIT WAVE FORM

 $\begin{array}{l} T_{ch}=25^{\circ}C \ (Initial) \\ Peak \ I_{AR}=-10 \ A, \ R_{G}=25 \ \Omega \end{array} \\ E_{AS}=\frac{1}{2} \cdot L \cdot I^{2} \cdot \ (\frac{BVDSS}{BVDSS-VDD}) \\ V_{DD}=-24 \ V, \ L=1.0 \ mH \end{array}$ 

150

VDS

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